Atomic Resolution Analytical Electron Microscope

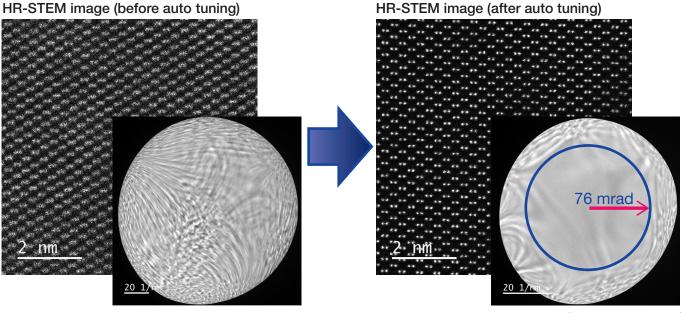
JEM-ARM200F

NEOARM



JEOL COSMO[™] Tune Auto tuning of aberration corrector Feedback of corrector parameter ASCOR Calculated by SRAM* method by using a pair of under and over focus Ronchigram patterns JEOL COSMO™ 50 35 - Defe Single Multi **NEOARM** Camera **Acquired Ronchigram**

*SRAM: Segmental Ronchigram Auto-correlation function Matrix



Ronchigram (before auto tuning)

Ronchigram (after auto tuning)

Acc vol: 200kV Sample: Si[110]

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